



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005 & ANSI/NCSL Z540-1-1994

Davis Calibration

171 South Gary Avenue, Carol Stream, IL 60188
Jeffrey Cea Phone: 630-933-7905

CALIBRATION

Valid to: June 12, 2012

Certificate Number: AC-1271

I. Electrical - DC/Low Frequency

Table with 5 columns: PARAMETER / EQUIPMENT, RANGE, BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (±)], REFERENCE STANDARD OR EQUIPMENT, METHOD(S). Rows include DC Voltage - Source, DC Voltage - Measure, and DC Current - Source.



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
DC Current - Measure	(10 to 100) μ A 100 μ A to 1 mA (1 to 10) mA (10 to 100) mA 100 mA to 1 A	20 μ A/A + 800 pA 20 μ A/A + 5 nA 20 μ A/A + 50 nA 35 μ A/A + 500 nA 105 μ A/A + 10 μ A	HP 3458A OPT 002	OEM or GIDEP Sourced or Locally Developed Procedures
AC Voltage – Source	Up to 33 mV (10 to 45) Hz 45 to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (33 to 330) mV (10 to 45) Hz 45 to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz 330 mV to 3.3 V (10 to 45) Hz 45 to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (3.3 to 33) V (10 to 45) Hz 45 to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (33 to 330) V (10 to 45) Hz 45 to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	550 μ V/V + 4.5 μ V 210 μ V/V + 4.5 μ V 105 μ V/V + 4.5 μ V 370 μ V/V + 4.5 μ V 850 μ V/V + 7 μ V 1.1 mV/V + 13 μ V 300 μ V/V + 8 μ V 145 μ V/V + 8 μ V 160 μ V/V + 8 μ V 350 μ V/V + 8 μ V 800 μ V/V + 32 μ V 2 mV/V + 70 μ V 300 μ V/V + 50 μ V 150 μ V/V + 60 μ V 190 μ V/V + 60 μ V 300 μ V/V + 50 μ V 700 μ V/V + 125 μ V 2.4 mV/V + 600 μ V 30 μ V/V + 650 μ V 150 μ V/V + 600 μ V 240 μ V/V + 600 μ V 350 μ V/V + 600 μ V 900 μ V/V + 1.6 mV 190 μ V/V + 2 mV 200 μ V/V + 6 mV 250 μ V/V + 6 mV 300 μ V/V + 6 mV 2 mV/V + 50 mV	Fluke 5520A-SC1100	



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Voltage – Source (cont.)	220 V to 1.1 kV 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	300 μ V/V + 10 mV 250 μ V/V + 10 mV 300 μ V/V + 10 mV	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
AC Voltage – Measure	(1 to 10) mV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1MHz (1 to 4) MHz (4 to 8) MHz (10 to 100) mV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 4) MHz (4 to 8) MHz (8 to 10) MHz 100 mV to 1 V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 4) MHz (4 to 8) MHz (8 to 10) MHz	300 μ V/V + 3 μ V 200 μ V/V + 1.1 μ V 300 μ V/V + 1.1 μ V 1 mV/V + 1.1 μ V 5 mV/V + 1.1 μ V 40 mV/V + 2 μ V 12 mV/V + 5 μ V 70 mV/V + 7 μ V 200 mV/V + 8 μ V 72 μ V/V + 4 μ V 72 μ V/V + 2 μ V 142 μ V/V + 2 μ V 302 μ V/V + 2 μ V 802 μ V/V + 2 μ V 30 mV/V + 10 μ V 10 mV/V + 10 μ V 15 mV/V + 10 μ V 40 mV/V + 8 μ V 150 mV/V + 100 μ V 72 μ V/V + 40 μ V 72 μ V/V + 20 μ V 142 μ V/V + 20 μ V 302 μ V/V + 20 μ V 802 μ V/V + 20 μ V 3 mV/V + 100 μ V 10 mV/V + 100 μ V 15 mV/V + 100 μ V 40 mV/V + 800 μ V 150 mV/V + 1 mV	HP 3458A OPT 002	



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Voltage – Measure (cont.)	(1 to 10) V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 4) MHz (4 to 8) MHz (8 to 10) MHz (10 to 100) V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz 100 V to 1 kV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	72 μ V/V + 400 μ V 72 μ V/V + 200 μ V 142 μ V/V + 200 μ V 302 μ V/V + 200 μ V 802 μ V/V + 200 μ V 3 mV/V + 1 mV 10 mV/V + 1 mV 15 mV/V + 1 mV 40 mV/V + 8 mV 150 mV/V + 10 mV 0.2 mV/V + 4 mV 0.2 mV/V + 2 mV 0.2 mV/V + 2 mV 0.35 mV/V + 2 mV 1.2 mV/V + 2 mV 4.0 mV/V + 10 mV 15 mV/V + 10 mV 400 μ V/V + 40 mV 400 μ V/V + 20 mV 600 μ V/V + 20 mV 1.2 mV/V + 20 mV 3 mV/V + 20 mV	HP 3458A OPT 002	OEM or GIDEP Sourced or Locally Developed Procedures
AC Current – Source	(29 to 330) μA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	2 mA/A + 100 nA 1.5 mA/A + 100 nA 1.25 mA/A + 100 nA 3 mA/A + 150 nA 8 mA/A + 200 nA 16 mA/A + 400 nA	Fluke 5520A-SC1100	



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Current – Source (cont.)	330 μA to 3.3 mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (3.3 to 33) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (33 to 330) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz 330 mA to 1.1 A (10 to 45) Hz 45 Hz to 1kHz (1 to 5) kHz (5 to 10) kHz (1.1 to 3) A (10 to 45) Hz 45 Hz to 1kHz (1 to 5) kHz (5 to 10) kHz (3 to 11) A (40 to 100) Hz 100 Hz to 1 kHz (1 to 50 kHz)	2 mA/A + 150 nA 1.25 mA/A + 150 nA 1 mA/A + 150 nA 2 mA/A + 200 nA 5 mA/A + 300 nA 10 mA/A + 600 nA 1.8 mA/A + 2 μ A 900 μ A/A + 2 μ A 400 μ A/A + 2 μ A 800 μ A/A + 2 μ A 2 mA/A + 3 μ A 4 mA/A + 4 μ A 1.8 mA/A + 20 μ A 900 μ A/A + 20 μ A 400 μ A/A + 20 μ A 1 mA/A + 50 μ A 2 mA/A + 100 μ A 4 mA/A + 200 μ A 1.8 mA/A + 100 μ A 500 μ A/A + 100 μ A 60 mA/A + 1 mA 25 mA/A + 5 mA 1.8 mA/A + 100 μ A 600 μ A/A + 100 μ A 60 mA/A + 1 mA 25 mA/A + 5 mA 600 μ A/A + 2 mA 1 mA/A + 2 mA 30 mA/A + 2 mA	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Current – Source (Cont.)	(11 to 20.5) A (40 to 100) Hz 100 Hz to 1 kHz (1 to 5k) Hz	1.2 mA/A + 5 mA 1.5 mA/A + 5 mA 30 mA/A + 5 mA	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
AC Current – Measure	(5 to 100) μA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 1 kHz 100 μA to 1 mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz (1 to 10) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz (10 to 100) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz	4 mA/A + 30 nA 1.5 mA/A + 30 nA 600 μ A/A + 30 nA 600 μ A/A + 30 nA 4 mA/A + 200 nA 1.5 mA/A + 200 nA 600 μ A/A + 200 nA 300 μ A/A + 200 nA 600 μ A/A + 200 nA 4 mA/A + 400 nA 5.5 mA/A + 1.5 μ A 4 mA/A + 2 μ A 1.5 mA/A + 2 μ A 600 μ A/A + 2 μ A 300 μ A/A + 2 μ A 600 μ A/A + 2 μ A 4 mA/A + 4 μ A 5.5 mA/A + 15 μ A 4 mA/A + 20 μ A 1.5 mA/A + 20 μ A 600 μ A/A + 20 μ A 300 μ A/A + 20 μ A 600 μ A/A + 20 μ A 4 mA/A + 40 μ A 5.5 mA/A + 150 μ A	HP 3458A OPT 002	



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Current – Measure (cont.)	100 mA to 1 A (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz	4 mA/A + 200 μ A 1.6 mA/A + 200 μ A 800 μ A/A + 200 μ A 1 mA/A + 200 μ A 3 mA/A + 200 μ A 10 mA/A + 400 μ A	HP 3458A OPT 002	OEM or GIDEP Sourced or Locally Developed Procedures
Resistance – Source	Up to 11 Ω (11 to 33) Ω (33 to 110) Ω (110 to 330) Ω 330 Ω to 1.1 k Ω (1.1 to 3.3) k Ω (3.3 to 11) k Ω (11 to 33) k Ω (33 to 110) k Ω (110 to 330) k Ω 330 k Ω to 1.1 M Ω (1.1 to 3.3) M Ω (3.3 to 11) M Ω (11 to 33) M Ω (33 to 110) M Ω (110 to 330) M Ω 330 M Ω to 1.1 G Ω	40 $\mu\Omega$ / Ω + 1 m Ω 30 $\mu\Omega$ / Ω + 1.5 m Ω 28 $\mu\Omega$ / Ω + 1.4 m Ω 28 $\mu\Omega$ / Ω + 2 m Ω 28 $\mu\Omega$ / Ω + 2 m Ω 28 $\mu\Omega$ / Ω + 20 m Ω 28 $\mu\Omega$ / Ω + 20 m Ω 28 $\mu\Omega$ / Ω + 200 m Ω 28 $\mu\Omega$ / Ω + 200 m Ω 32 $\mu\Omega$ / Ω + 2 Ω 32 $\mu\Omega$ / Ω + 2 Ω 60 $\mu\Omega$ / Ω + 30 Ω 130 $\mu\Omega$ / Ω + 50 Ω 250 $\mu\Omega$ / Ω + 2.5 k Ω 500 $\mu\Omega$ / Ω + 3 k Ω 3 m Ω / Ω + 100 k Ω 15 m Ω / Ω + 500 k Ω	Fluke 5520A-SC1100	
Resistance - Measure	Up to 10 Ω (10 to 100) Ω 100 Ω to 1 k Ω (1 to 10) k Ω (10 to 100) k Ω 100 k Ω to 1 M Ω (1 to 10) M Ω (10 to 100) M Ω 100 M Ω to 1 G Ω	18 $\mu\Omega$ / Ω + 50 $\mu\Omega$ 13 $\mu\Omega$ / Ω + 500 $\mu\Omega$ 11 $\mu\Omega$ / Ω + 500 $\mu\Omega$ 11 $\mu\Omega$ / Ω + 5 m Ω 11 $\mu\Omega$ / Ω + 50 m Ω 15 $\mu\Omega$ / Ω + 2 Ω 53 $\mu\Omega$ / Ω + 100 Ω 503 $\mu\Omega$ / Ω + 1 k Ω 5 m Ω / Ω + 10 k Ω	HP 3458A OPT 002	



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Electrical Simulation of Thermocouple Indicators			Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
Type B	(600 to 800) °C	0.51 °C		
	(800 to 1 000) °C	0.39 °C		
	(1 000 to 1 550) °C	0.35 °C		
	(1 550 to 1 820) °C	0.38 °C		
Type C	(0 to 150) °C	0.35 °C		
	(150 to 650) °C	0.3 °C		
	(650 to 1 000) °C	0.36 °C		
	(1 000 to 1 800) °C	0.58 °C		
	(1 800 to 2 316) °C	0.97 °C		
Type E	(-250 to -100) °C	0.58 °C		
	(-100 to -25) °C	0.19 °C		
	(-25 to 350) °C	0.16 °C		
	(350 to 650) °C	0.19 °C		
	(650 to 1 000) °C	0.24 °C		
Type J	(-210 to -100) °C	0.32 °C		
	(-100 to -30) °C	0.19 °C		
	(-30 to 150) °C	0.17 °C		
	(150 to 760) °C	0.2 °C		
	(760 to 1 200) °C	0.27 °C		
Type K	(-200 to -100) °C	0.38 °C		
	(-100 to -25) °C	0.21 °C		
	(-25 to 120) °C	0.19 °C		
	(120 to 1 000) °C	0.3 °C		
	(1 000 to 1 372) °C	0.46 °C		
Type L	(-200 to -100) °C	0.43 °C		
	(-100 to 800) °C	0.3 °C		
	(800 to 900) °C	0.2 °C		
Type N	(-200 to -100) °C	0.46 °C		
	(-100 to -25) °C	0.25 °C		
	(-25 to 120) °C	0.22 °C		
	(120 to 410) °C	0.21 °C		
	(410 to 1 300) °C	0.31 °C		



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Type R Type S Type T Type U	(0 to 250) °C (250 to 400) °C (400 to 1 000) °C (1 000 to 1 767) °C (0 to 250) °C (250 to 1 000) °C (1 000 to 1 400) °C (1 400 to 1 767) °C (-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C (-200 to 0) °C (0 to 600) °C	0.66 °C 0.4 °C 0.38 °C 0.46 °C 0.54 °C 0.42 °C 0.43 °C 0.53 °C 0.73 °C 0.28 °C 0.19 °C 0.17 °C 0.65 °C 0.31 °C	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
Electrical Simulation of RTDs Pt 385 (100 Ω) Pt 3926 (100 Ω)	(-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C (-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C	0.06 °C 0.08 °C 0.1 °C 0.12 °C 0.14 °C 0.27 °C 0.06 °C 0.08 °C 0.1 °C 0.12 °C 0.14 °C		



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Pt 3916 (100 Ω)	(-200 to -190) °C	0.29 °C	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
	(-190 to -80) °C	0.05 °C		
	(-80 to 0) °C	0.06 °C		
	(0 to 100) °C	0.07 °C		
	(100 to 260) °C	0.08 °C		
	(260 to 300) °C	0.09 °C		
	(300 to 400) °C	0.1 °C		
	(400 to 600) °C	0.12 °C		
Pt 385 (200 Ω)	(-200 to 100) °C	0.05 °C	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
	(100 to 260) °C	0.06 °C		
	(260 to 300) °C	0.14 °C		
	(300 to 400) °C	0.15 °C		
	(400 to 600) °C	0.16 °C		
	(600 to 630) °C	0.18 °C		
Pt 385 (500 Ω)	(-200 to -80) °C	0.05 °C	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
	(-80 to 100) °C	0.06 °C		
	(100 to 260) °C	0.07 °C		
	(260 to 400) °C	0.09 °C		
	(400 to 600) °C	0.1 °C		
	(600 to 630) °C	0.13 °C		
Pt 385 (1 000 Ω)	(-200 to 0) °C	0.03 °C	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
	(0 to 100) °C	0.05 °C		
	(100 to 260) °C	0.06 °C		
	(260 to 300) °C	0.07 °C		
	(300 to 600) °C	0.08 °C		
	(600 to 630) °C	0.27 °C		
PtNi 385 (120 Ω)	(-80 to 100) °C	0.09 °C	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
	(100 to 260) °C	0.16 °C		



PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Capacitance – Source 10Hz to 10kHz 10Hz to 10kHz 10Hz to 3kHz 10Hz to 1kHz 10Hz to 1kHz 10Hz to 1kHz 10Hz to 1kHz (10 to 600) Hz (10 to 300) Hz (10 to 150) Hz (10 to 120) Hz (10 to 80) Hz (0 to 50) Hz (0 to 20) Hz (0 to 6) Hz (0 to 2) Hz (0 to 0.6) Hz (0 to 0.2) Hz	190 to 400 pF 400 pF to 1.1 nF (1.1 to 3.3) nF (3.3 to 11) nF (11 to 33) nF (33 to 110) nF (110 to 330) nF 330 nF to 1.1 μ F (1.1 to 3.3) μ F (3.3 to 11) μ F (11 to 33) μ F (110 to 330) μ F 330 μ F to 1.1 mF (1.1 to 3.3) mF (3.3 to 11) mF (11 to 33) mF (33 to 110) mF	5 mF + 10 pF 5 mF + 10 pF 5 mF + 10 pF 5 mF + 10 pF 2.5 mF + 100 pF 2.5 mF + 100 pF 2.5 mF + 300 pF 2.5 mF + 1 nF 3.5 mF + 3 nF 3.5 mF + 10 nF 4 mF + 30 nF 5 mF + 100 nF 7 mF + 300 nF 10 mF + 300 nF 4.5 mF + 3 μ F 4.5 mF + 10 μ F 7.5 mF + 30 μ F 11 mF + 100 μ F	Fluke 5520A-SC1100	OEM or GIDEP Sourced or Locally Developed Procedures
Calibration of Oscilloscopes Amplitude DC Signal into 50 Ω Load into 1 M Ω Load Amplitude Square Wave 50 Ω Load 1 M Ω Load Leveled Sine Wave - Flatness Relative to 50 kHz [5 mV to 5.5 V] [5 mV to 3.5 V]	(-6.6 to 6.6) V (-130 to 130) V 1 mV to 6.6 Vp-p 10 Hz to 10 kHz 1 mV to 130 Vp-p 10 Hz to 10 kHz 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 600 MHz to 1.1 GHz	2.5 mV/V + 40 μ V 500 μ V/V + 40 μ V 2.5 mV/V + 40 μ V 1 mV/V + 40 μ V 15 mV/V + 100 μ V 20 mV/V + 100 μ V 40 mV/V + 100 μ V 50 mV/V + 100 μ V		



II. Time and Frequency

PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Frequency - Source	0.01 Hz to 2 MHz 10 MHz	2.6 μ Hz/Hz + 5 μ Hz 1 part in 10^{-9}	Fluke 5520A-SC1100 Efratom M100	OEM or GIDEP Sourced or Locally Developed Procedures
Frequency - Measure	DC to 1.3GHz	1 part in 10^{-9}	Efratom M100 w/ HP 53132A	

III. Dimensional

PARAMETER / EQUIPMENT	RANGE	BEST MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY (\pm)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Micrometers	Up to 12 in (12 to 36) in	(60 + 5L) μ in (120 + 8L) μ in	Grade 2 Gage Blocks	OEM or GIDEP Sourced or Locally Developed Procedures
Calipers	Up to 12 in (12 to 40) in	150 μ in (150 + 10L) μ in		
Indicators	Up to 6 in	(50 + 0.5L) μ in	Pratt & Whitney Supermicrometer with Grade 2 Gage Blocks	
*Plain Plug and Pin Gages	Up to 8 in	(35 + 4L) μ in		
*Thread Plugs	Up to 5 in	150 μ in	Pratt & Whitney Supermicrometer with Grade 2 Gage Blocks and Thread Wires	

Notes:

1. Best Measurement Capabilities (Expanded Uncertainties) are based on approximately a 95% confidence interval, using a coverage of $k=2$.
2. This laboratory's capabilities include both laboratory and field (on-site) calibration services. Since field conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected in the field than what is reported on the accredited scope.
3. Capabilities denoted by an asterisk (*) are laboratory only, not available for field calibration activity.
4. The use of (L) signifies an expression of Length in inches.
5. The use of (t) signifies an expression of Time in seconds.
6. This scope is part of and must be included with the Certificate of Accreditation No. AC-1271.

Karl Greenway

Vice President

Page 13 of 13

